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## Intel - 5SGSMD8N2F45I2N Datasheet



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	262400
Number of Logic Elements/Cells	695000
Total RAM Bits	51200000
Number of I/O	840
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1932-BBGA, FCBGA
Supplier Device Package	1932-FBGA, FC (45x45)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgsmd8n2f45i2n

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This section lists the functional operating limits for the AC and DC parameters for Stratix V devices. Table 6 lists the steady-state voltage and current values expected from Stratix V devices. Power supply ramps must all be strictly monotonic, without plateaus.

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 1 of 2)

Symbol	Description	Condition	Min <sup>(4)</sup>	Тур	Max <sup>(4)</sup>	Unit
	Core voltage and periphery circuitry power supply (C1, C2, I2, and I3YY speed grades)	_	0.87	0.9	0.93	V
V <sub>CC</sub>	Core voltage and periphery circuitry power supply (C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) <sup>(3)</sup>	_	0.82	0.85	0.88	V
V <sub>CCPT</sub>	Power supply for programmable power technology	_	1.45	1.50	1.55	V
V <sub>CC_AUX</sub>	Auxiliary supply for the programmable power technology	_	2.375	2.5	2.625	V
VI (1)	I/O pre-driver (3.0 V) power supply	_	2.85	3.0	3.15	V
V <sub>CCPD</sub> <sup>(1)</sup>	I/O pre-driver (2.5 V) power supply	_	2.375	2.5	2.625	V
	I/O buffers (3.0 V) power supply		2.85	3.0	3.15	V
	I/O buffers (2.5 V) power supply	_	2.375	2.5	2.625	V
	I/O buffers (1.8 V) power supply		1.71	1.8	1.89	V
V <sub>CCIO</sub>	I/O buffers (1.5 V) power supply	_	1.425	1.5	1.575	V
	I/O buffers (1.35 V) power supply	_	1.283	1.35	1.45	V
	I/O buffers (1.25 V) power supply	_	1.19	1.25	1.31	V
	I/O buffers (1.2 V) power supply	_	1.14	1.2	1.26	V
	Configuration pins (3.0 V) power supply	_	2.85	3.0	3.15	V
V <sub>CCPGM</sub>	Configuration pins (2.5 V) power supply	_	2.375	2.5	2.625	V
	Configuration pins (1.8 V) power supply	_	1.71	1.8	1.89	V
V <sub>CCA_FPLL</sub>	PLL analog voltage regulator power supply	_	2.375	2.5	2.625	V
V <sub>CCD_FPLL</sub>	PLL digital voltage regulator power supply	_	1.45	1.5	1.55	V
V <sub>CCBAT</sub> (2)	Battery back-up power supply (For design security volatile key register)	_	1.2	_	3.0	V
VI	DC input voltage	_	-0.5	_	3.6	V
V <sub>0</sub>	Output voltage	—	0	—	V <sub>CCIO</sub>	V
т	Operating junction temperature	Commercial	0	—	85	°C
TJ	Operating junction temperature	Industrial	-40	_	100	°C

			Resistance Tolerance					
Symbol	Description	Conditions	C1	C2,I2	C3, I3, I3YY	C4, I4	Unit	
50-Ω R <sub>S</sub>	Internal series termination without calibration (50- $\Omega$ setting)	$V_{CCIO} = 1.8$ and 1.5 V	±30	±30	±40	±40	%	
50-Ω R <sub>S</sub>	Internal series termination without calibration (50- $\Omega$ setting)	V <sub>CCI0</sub> = 1.2 V	±35	±35	±50	±50	%	
100-Ω R <sub>D</sub>	Internal differential termination (100- $\Omega$ setting)	V <sub>CCPD</sub> = 2.5 V	±25	±25	±25	±25	%	

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

### Equation 1. OCT Variation Without Recalibration for Stratix V Devices (1), (2), (3), (4), (5), (6)

$$R_{OCT} \,=\, R_{SCAL} \Big( 1 + \langle \frac{dR}{dT} \times \Delta T \rangle \pm \langle \frac{dR}{dV} \times \Delta V \rangle \Big)$$

#### Notes to Equation 1:

- (1) The  $R_{OCT}$  value shows the range of OCT resistance with the variation of temperature and  $V_{CCIO}$ .
- (2) R<sub>SCAL</sub> is the OCT resistance value at power-up.
- (3)  $\Delta T$  is the variation of temperature with respect to the temperature at power-up.
- (4)  $\Delta V$  is the variation of voltage with respect to the V<sub>CCIO</sub> at power-up.
- (5) dR/dT is the percentage change of  $R_{\text{SCAL}}$  with temperature.
- (6) dR/dV is the percentage change of  $\mathsf{R}_{\mathsf{SCAL}}$  with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13.	OCT Variation after Power-U	Calibration for Stratix V Devices	(Part 1 of 2) <sup>(1)</sup>
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Symbol	Description	V <sub>CCIO</sub> (V)	Typical	Unit
		3.0	0.0297	
		2.5	0.0344	
dR/dV	R/dV OCT variation with voltage without recalibration	1.8	0.0499	%/mV
	recampration		0.0744	
		1.2	0.1241	

## **Switching Characteristics**

This section provides performance characteristics of the Stratix V core and periphery blocks.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The title of these tables show the designation as "Preliminary."
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

## **Transceiver Performance Specifications**

This section describes transceiver performance specifications.

Table 23 lists the Stratix V GX and GS transceiver specifications.

Table 23.	<b>Transceiver S</b>	necifications (	for Stratix	V GX and GS	Devices (1)	(Part 1 of 7)
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Symbol/ Description	Conditions	Trai	isceive Grade	r Speed 1	Trar	isceive Grade	r Speed 2	Trar	isceive Grade	r Speed 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
<b>Reference Clock</b>											
Supported I/O Standards	Dedicated reference clock pin	1.2-V	PCML,	1.4-V PCM	L, 1.5-V		, 2.5-V PCN HCSL	1L, Diffe	rential	LVPECL, L\	/DS, and
Standards	RX reference clock pin			1.4-V PCMI	_, 1.5-V	PCML,	2.5-V PCM	L, LVPE	CL, and	d LVDS	
Input Reference Clock Frequency (CMU PLL) <sup>(8)</sup>	_	40	_	710	40	_	710	40	_	710	MHz
Input Reference Clock Frequency (ATX PLL) <sup>(8)</sup>	_	100		710	100		710	100	_	710	MHz
Rise time	Measure at ±60 mV of differential signal <sup>(26)</sup>	_	_	400	_	_	400	_	_	400	ps
Fall time	Measure at ±60 mV of differential signal <sup>(26)</sup>	_	— — 400				400	_		400	μο
Duty cycle	—	45		55	45		55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express® (PCIe <sup>®</sup> )	30		33	30		33	30		33	kHz

Symbol/	Conditions	Trai	nsceive Grade	r Speed 1	Trai	nsceive Grade	r Speed 2	Trai	nsceive Grade	r Speed 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Spread-spectrum downspread	PCle	_	0 to 0.5	_	_	0 to 0.5		_	0 to 0.5	_	%
On-chip termination resistors <sup>(21)</sup>	_	_	100		_	100		_	100		Ω
Absolute V <sub>MAX</sub> <sup>(5)</sup>	Dedicated reference clock pin	_	_	1.6	_	_	1.6	_	_	1.6	V
	RX reference clock pin	_	_	1.2	_		1.2		_	1.2	
Absolute $V_{\text{MIN}}$	—	-0.4	—		-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	_	200	_	1600	200	_	1600	200	_	1600	mV
V <sub>ICM</sub> (AC	Dedicated reference clock pin	1050/	1050/1000/900/850 <sup>(2)</sup>		1050/1000/900/850 (2)			1050/	mV		
coupled) <sup>(3)</sup>	RX reference clock pin	1.	1.0/0.9/0.85 <sup>(4)</sup>		1.	1.0/0.9/0.85 <sup>(4)</sup>			0/0.9/0	.85 <sup>(4)</sup>	V
V <sub>ICM</sub> (DC coupled)	HCSL I/O standard for PCIe reference clock	250		550	250		550	250		550	mV
	100 Hz	—	—	-70	—	—	-70	—	—	-70	dBc/Hz
Transmitter	1 kHz			-90			-90		—	-90	dBc/Hz
REFCLK Phase Noise	10 kHz	—	—	-100	—	—	-100	—	—	-100	dBc/Hz
(622 MHz) <sup>(20)</sup>	100 kHz			-110		—	-110	—	—	-110	dBc/Hz
	≥1 MHz	—	—	-120	—	—	-120	—	—	-120	dBc/Hz
Transmitter REFCLK Phase Jitter (100 MHz) <sup>(17)</sup>	10 kHz to 1.5 MHz (PCle)	_	_	3	_	_	3	_	_	3	ps (rms)
R <sub>REF</sub> (19)	_		1800 ±1%		_	1800 ±1%	_		180 0 ±1%		Ω
Transceiver Clocks	S										
fixedclk clock frequency	PCIe Receiver Detect		100 or 125	_	_	100 or 125	_	_	100 or 125	_	MHz

## Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 2 of 7)

Symbol/	Conditions	Trai	nsceive Grade	r Speed 1	Trai	nsceive Grade	r Speed 2	Transceiver Speed Grade 3			Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Reconfiguration clock (mgmt_clk_clk) frequency	_	100	_	125	100		125	100		125	MHz
Receiver											
Supported I/O Standards	_			1.4-V PCM	L, 1.5-V	PCML,	2.5-V PCM	L, LVPE	CL, and	d LVDS	
Data rate (Standard PCS) (9), (23)	_	600	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$								
Data rate (10G PCS) <sup>(9),</sup> <sup>(23)</sup>		600	_	14100	600	_	12500	600	_	8500/ 10312.5 (24)	Mbps
Absolute $V_{MAX}$ for a receiver pin $(5)$		_	_	1.2	—	_	1.2	—	_	1.2	V
Absolute V <sub>MIN</sub> for a receiver pin	_	-0.4	_		-0.4	_	_	-0.4	_	_	V
Maximum peak- to-peak differential input voltage V <sub>ID</sub> (diff p- p) before device configuration <sup>(22)</sup>	_	_	_	1.6	_	_	1.6	_	_	1.6	V
Maximum peak- to-peak	V <sub>CCR_GXB</sub> = 1.0 V/1.05 V (V <sub>ICM</sub> = 0.70 V)	_	_	2.0	_	_	2.0	_	_	2.0	V
differential input voltage $V_{ID}$ (diff p- p) after device configuration <sup>(18)</sup> ,	$V_{CCR_GXB} = 0.90 V$ (V <sub>ICM</sub> = 0.6 V)	_	_	2.4	_	_	2.4	_	_	2.4	V
(22)	$V_{CCR\_GXB} = 0.85 V$ (V <sub>ICM</sub> = 0.6 V)			2.4			2.4			2.4	V
Minimum differential eye opening at receiver serial input pins <sup>(6), (22),</sup> (27)	_	85		_	85	_	_	85	_	_	mV

## Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 3 of 7)

Symbol/ Description	Conditions	Tra	nsceive Grade	r Speed 1	Tra	nsceive Grade	r Speed 2	Trai	nsceive Grade	r Speed 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
	85– $\Omega$ setting		85 ± 30%		—	85 ± 30%			85 ± 30%		Ω
Differential on-	100–Ω setting	_	100 ± 30%		_	100 ± 30%		_	100 ± 30%		Ω
chip termination resistors <sup>(21)</sup>	120–Ω setting	_	120 ± 30%		_	120 ± 30%		_	120 ± 30%		Ω
	150-Ω setting	_	150 ± 30%	_	_	150 ± 30%		_	150 ± 30%		Ω
	V <sub>CCR_GXB</sub> = 0.85 V or 0.9 V full bandwidth		600		_	600	_		600		mV
V <sub>ICM</sub> (AC and DC coupled)	$bandwidth \\ V_{CCR_GXB} = \\ 0.85 V \text{ or } 0.9 \\ V \\ half \\ bandwidth \\ \end{cases}$	_	600	_	_	600	_	_	600	_	mV
coupleu)	V <sub>CCR_GXB</sub> = 1.0 V/1.05 V full bandwidth	_	700		_	700			700		mV
	V <sub>CCR_GXB</sub> = 1.0 V half bandwidth	_	750	_	_	750	_	_	750	_	mV
t <sub>LTR</sub> <sup>(11)</sup>	_	_	—	10	—	—	10	—	—	10	μs
t <sub>LTD</sub> (12)	_	4			4			4			μs
t <sub>LTD_manual</sub> <sup>(13)</sup>		4			4			4	_		μs
t <sub>LTR_LTD_manual</sub> <sup>(14)</sup>		15			15	—		15	—		μs
Run Length	_	_		200		—	200		—	200	UI
Programmable equalization (AC Gain) <sup>(10)</sup>	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)			16	_		16	_		16	dB

 Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 4 of 7)

Table 24 shows the maximum transmitter data rate for the clock network.

Table 24. Clock Network Maximum Data Rate Transmitter Specifications (1)

		ATX PLL			CMU PLL <sup>(2)</sup>	)		fPLL	
Clock Network	Non- bonded Mode (Gbps)	Bonded Mode (Gbps)	Channel Span	Non- bonded Mode (Gbps)	Bonded Mode (Gbps)	Channel Span	Non- bonded Mode (Gbps)	Bonded Mode (Gbps)	Channel Span
x1 <sup>(3)</sup>	14.1	—	6	12.5	_	6	3.125	_	3
x6 <sup>(3)</sup>	_	14.1	6	_	12.5	6	_	3.125	6
x6 PLL Feedback <sup>(4)</sup>	_	14.1	Side- wide	_	12.5	Side- wide		_	_
xN (PCIe)	_	8.0	8	_	5.0	8	_	_	_
VN (Native DHV ID)	8.0	8.0	Up to 13 channels above and below PLL	7.99	7.99	Up to 13 channels above	3.125	3.125	Up to 13 channels above
xN (Native PHY IP)	_	8.01 to 9.8304	Up to 7 channels above and below PLL	7.55	7.55	and below PLL	3.120	0.120	and below PLL

Notes to Table 24:

(1) Valid data rates below the maximum specified in this table depend on the reference clock frequency and the PLL counter settings. Check the MegaWizard message during the PHY IP instantiation.

(2) ATX PLL is recommended at 8 Gbps and above data rates for improved jitter performance.

(3) Channel span is within a transceiver bank.

(4) Side-wide channel bonding is allowed up to the maximum supported by the PHY IP.

Mada (2)	Transceiver	PMA Width	20	20	16	16	10	10	8	8
Mode <sup>(2)</sup>	Speed Grade	PCS/Core Width	40	20	32	16	20	10	16	8
	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
	2	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
	2	C3, I3, I3L core speed grade	9.8	9.0	7.84	7.2	5.3	4.7	4.24	3.76
FIFO		C1, C2, C2L, I2, I2L core speed grade	8.5	8.5	8.5	8.5	6.5	5.8	5.2	4.72
	3	I3YY core speed grade	10.3125	10.3125	7.84	7.2	5.3	4.7	4.24	3.76
	3	C3, I3, I3L core speed grade	8.5	8.5	7.84	7.2	5.3	4.7	4.24	3.76
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.8	4.2	3.84	3.44
	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
	2	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
	2	C3, I3, I3L core speed grade	9.8	9.0	7.92	7.2	4.9	4.5	3.96	3.6
Register		C1, C2, C2L, I2, I2L core speed grade	10.3125	10.3125	10.3125	10.3125	6.1	5.7	4.88	4.56
	3 -	I3YY core speed grade	10.3125	10.3125	7.92	7.2	4.9	4.5	3.96	3.6
		C3, I3, I3L core speed grade	8.5	8.5	7.92	7.2	4.9	4.5	3.96	3.6
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.4	4.1	3.52	3.28

Table 25 shows the approximate maximum data rate using the standard PCS.

Table 25. Stratix V Standard PCS Approximate Maximum Date Rate (1), (3)

Notes to Table 25:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

(3) The maximum data rate is also constrained by the transceiver speed grade. Refer to Table 1 for the transceiver speed grade.

Symbol/	Conditions Transceive		Transceiver Speed Grade				Fransceiver Deed Grade 3	
Description		Min	Тур	Max	Min	Тур	Max	r
Differential on-chip termination resistors <sup>(7)</sup>	GT channels		100	_	_	100	_	Ω
	85- $\Omega$ setting	_	85 ± 30%	_	_	85 ± 30%	_	Ω
Differential on-chip termination resistors	100-Ω setting	_	100 ± 30%	_	_	100 ± 30%	_	Ω
for GX channels <sup>(19)</sup>	120-Ω setting	_	120 ± 30%	_	_	120 ± 30%	_	Ω
	150-Ω setting		150 ± 30%	_	_	150 ± 30%	_	Ω
V <sub>ICM</sub> (AC coupled)	GT channels		650		—	650	—	mV
	VCCR_GXB = 0.85 V or 0.9 V		600	_	_	600		mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 1.0 V full bandwidth		700	_	_	700	_	mV
	VCCR_GXB = 1.0 V half bandwidth		750	_	_	750	_	mV
t <sub>LTR</sub> <sup>(9)</sup>	—	—	—	10	—	—	10	μs
t <sub>LTD</sub> <sup>(10)</sup>		4			4			μs
t <sub>LTD_manual</sub> <sup>(11)</sup>	—	4	—	—	4	—	_	μs
t <sub>LTR_LTD_manual</sub> <sup>(12)</sup>	_	15			15	—		μs
Run Length	GT channels	_	_	72	—	—	72	CID
nun Lengin	GX channels				(8)			
CDR PPM	GT channels			1000	_	—	1000	± PPM
	GX channels				(8)			
Programmable	GT channels	_	_	14	—	—	14	dB
equalization (AC Gain) <sup>(5)</sup>	GX channels				(8)			
Programmable	GT channels	_	—	7.5	—	—	7.5	dB
DC gain <sup>(6)</sup>	GX channels				(8)			
Differential on-chip termination resistors <sup>(7)</sup>	GT channels	_	100	_	_	100	_	Ω
Transmitter	·1							
Supported I/O Standards	_	1.4-V and 1.5-V PCML						
Data rate (Standard PCS)	GX channels	600	_	8500	600	_	8500	Mbps
Data rate (10G PCS)	GX channels	600		12,500	600	_	12,500	Mbps

## Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5)<sup>(1)</sup>

Table 29 shows the  $V_{\text{OD}}$  settings for the GT channel.

Table 29.	Typical Von Setting	g for GT Channel, T	<b>EX Termination = 100</b> $\Omega$
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Symbol	V <sub>OD</sub> Setting	V <sub>op</sub> Value (mV)
	0	0
	1	200
$\mathbf{V}_{0D}$ differential peak to peak typical (1)	2	400
VOD unicicilitat peak to peak typical (*)	3	600
	4	800
	5	1000

#### Note:

(1) Refer to Figure 4.

Figure 4 shows the differential transmitter output waveform.





Figure 5 shows the Stratix V AC gain curves for GT channels.

Figure 5. AC Gain Curves for GT Channels

- XFI
- ASI
- HiGig/HiGig+
- HiGig2/HiGig2+
- Serial Data Converter (SDC)
- GPON
- SDI
- SONET
- Fibre Channel (FC)
- PCIe
- QPI
- SFF-8431

Download the Stratix V Characterization Report Tool to view the characterization report summary for these protocols.

## **Core Performance Specifications**

This section describes the clock tree, phase-locked loop (PLL), digital signal processing (DSP), memory blocks, configuration, and JTAG specifications.

## **Clock Tree Specifications**

Table 30 lists the clock tree specifications for Stratix V devices.

Table 30. Clock Tree Performance for Stratix V Devices (1)

		Performance			
Symbol	C1, C2, C2L, I2, and I2L	C3, I3, I3L, and I3YY	C4, I4	Unit	
Global and Regional Clock	717	650	580	MHz	
Periphery Clock	550	500	500	MHz	

#### Note to Table 30:

(1) The Stratix V ES devices are limited to 600 MHz core clock tree performance.

Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is 1.

Table 50. FPP Timing Parameters for Stratix V Devices (1)

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	—	μS
t <sub>status</sub>	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(3)</sup>	μS
t <sub>CF2CK</sub> (6)	nCONFIG high to first rising edge on DCLK	1,506	_	μS
t <sub>ST2CK</sub> <sup>(6)</sup>	nSTATUS high to first rising edge of DCLK	2	_	μS
t <sub>DSU</sub>	DATA [] setup time before rising edge on DCLK	5.5	_	ns
t <sub>DH</sub>	DATA [] hold time after rising edge on DCLK	0	_	ns
t <sub>CH</sub>	DCLK high time	$0.45\times1/f_{MAX}$	—	S
t <sub>CL</sub>	DCLK low time	$0.45\times1/f_{MAX}$	—	S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>	_	S
f	DCLK frequency (FPP ×8/×16)	—	125	MHz
f <sub>MAX</sub>	DCLK frequency (FPP ×32)	—	100	MHz
t <sub>CD2UM</sub>	CONF_DONE high to user mode <sup>(4)</sup>	175	437	μS
+	CONTRACT high to an union analysis	4 × maximum		
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	DCLK period	—	
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$\begin{array}{c} t_{\text{CD2CU}} + \\ (8576 \times \text{CLKUSR} \\ \text{period}) \ ^{(5)} \end{array}$	_	_

#### Notes to Table 50:

(1) Use these timing parameters when the decompression and design security features are disabled.

(2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.

(3) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.

- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (6) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

## FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.



#### Figure 13. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1 (1), (2)

#### Notes to Figure 13:

- (1) Use this timing waveform and parameters when the DCLK-to-DATA [] ratio is >1. To find out the DCLK-to-DATA [] ratio for your system, refer to Table 49 on page 55.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nSTATUS low for the time as specified by the POR delay.
- (4) After power-up, before and during configuration, CONF\_DONE is low.
- (5) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (6) "r" denotes the DCLK-to-DATA [] ratio. For the DCLK-to-DATA [] ratio based on the decompression and the design security feature enable settings, refer to Table 49 on page 55.
- (7) If needed, pause DCLK by holding it low. When DCLK restarts, the external host must provide data on the DATA [31..0] pins prior to sending the first DCLK rising edge.
- (8) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (9) After the option bit to enable the INIT DONE pin is configured into the device, the INIT DONE goes low.

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Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is more than 1.

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	_	μS
t <sub>STATUS</sub>	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	μS
t <sub>CF2CK</sub> <sup>(5)</sup>	nCONFIG high to first rising edge on DCLK	1,506	_	μS
t <sub>ST2CK</sub> <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μS
t <sub>DSU</sub>	DATA [] setup time before rising edge on DCLK	5.5		ns
t <sub>DH</sub>	DATA [] hold time after rising edge on DCLK	N-1/f <sub>DCLK</sub> <sup>(5)</sup>		S
t <sub>CH</sub>	DCLK high time	$0.45  imes 1/f_{MAX}$		S
t <sub>CL</sub>	DCLK low time	$0.45\times1/f_{MAX}$		S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>		S
f	DCLK frequency (FPP ×8/×16)	—	125	MHz
f <sub>MAX</sub>	DCLK frequency (FPP ×32)	—	100	MHz
t <sub>R</sub>	Input rise time	—	40	ns
t <sub>F</sub>	Input fall time	—	40	ns
t <sub>CD2UM</sub>	CONF_DONE high to user mode <sup>(3)</sup>	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	_
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU}$ + (8576 × CLKUSR period) <sup>(4)</sup>	_	_

#### Notes to Table 51:

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (5) N is the  ${\tt DCLK}\mbox{-to-DATA}$  ratio and  $f_{{\tt DCLK}}$  is the  ${\tt DCLK}$  frequency the system is operating.
- (6) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

## **Active Serial Configuration Timing**

Table 52 lists the DCLK frequency specification in the AS configuration scheme.

Table 52.	DCLK Frequency	Specification in the <i>l</i>	AS Configuration Scheme	(1), (2)
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Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

#### Notes to Table 52:

(1) This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.

(2) The AS multi-device configuration scheme does not support DCLK frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.





#### Notes to Figure 14:

- (1) If you are using AS  $\times 4$  mode, this signal represents the AS\_DATA[3..0] and EPCQ sends in 4-bits of data for each DCLK cycle.
- (2) The initialization clock can be from internal oscillator or CLKUSR pin.
- (3) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.

Table 53 lists the timing parameters for AS  $\times 1$  and AS  $\times 4$  configurations in Stratix V devices.

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CO</sub>	DCLK falling edge to AS_DATA0/ASDO output	—	2	ns
t <sub>SU</sub>	Data setup time before falling edge on DCLK	1.5	—	ns
t <sub>H</sub>	Data hold time after falling edge on DCLK	0	—	ns

Table 54 lists the PS configuration timing parameters for Stratix V devices.

Table 54. PS Timing Parameters for Stratix V Devices

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	—	μS
t <sub>status</sub>	nSTATUS low pulse width	268	1,506 <sup>(1)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	μS
t <sub>CF2CK</sub> (5)	nCONFIG high to first rising edge on DCLK	1,506	—	μS
t <sub>ST2CK</sub> <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μS
t <sub>DSU</sub>	DATA[] setup time before rising edge on DCLK	5.5	—	ns
t <sub>DH</sub>	DATA[] hold time after rising edge on DCLK	0	—	ns
t <sub>CH</sub>	DCLK high time	$0.45\times 1/f_{MAX}$	—	S
t <sub>CL</sub>	DCLK low time	$0.45\times 1/f_{MAX}$	—	S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>	—	S
f <sub>MAX</sub>	DCLK frequency	—	125	MHz
t <sub>CD2UM</sub>	CONF_DONE high to user mode $(3)$	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	_
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU}$ + (8576 × CLKUSR period) <sup>(4)</sup>	_	_

#### Notes to Table 54:

(1) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.

(2) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.

(3) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

(4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the "Initialization" section.

(5) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

## Initialization

Table 55 lists the initialization clock source option, the applicable configuration schemes, and the maximum frequency.

Table 55. Initialization Clock Source Option and the Maximu
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Initialization Clock Source	Configuration Schemes	Maximum Frequency	Minimum Number of Clock Cycles <sup>(1)</sup>
Internal Oscillator	AS, PS, FPP	12.5 MHz	
CLKUSR	AS, PS, FPP <sup>(2)</sup>	125 MHz	8576
DCLK	PS, FPP	125 MHz	

#### Notes to Table 55:

(1) The minimum number of clock cycles required for device initialization.

(2) To enable CLKUSR as the initialization clock source, turn on the Enable user-supplied start-up clock (CLKUSR) option in the Quartus II software from the General panel of the Device and Pin Options dialog box.

## Table 60. Glossary (Part 2 of 4)

Letter	Subject	Definitions
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Н	_	_
Ι		
J	J JTAG Timing Specifications	High-speed I/O block—Deserialization factor (width of parallel data bus). JTAG Timing Specifications: TMS TDI $t_{JCP}$ $t_{JCP}$ $t_{JPCO}$ $t_{JPCO}$ $t_{JPXZ}$ TDO $t_{JPXZ}$ $t_{JPXZ}$
K L M N O	_	_
Ρ	PLL Specifications	Diagram of PLL Specifications (1)
Q		_
	1	

Table 60.	Glossary	(Part 3 of 4)
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Letter	Subject	Definitions		
	SW (sampling window)	Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown:         Bit Time         0.5 x TCCS       RSKM         Sampling Window       RSKM         0.5 x TCCS       RSKM		
S	Single-ended voltage referenced I/O standard	The JEDEC standard for <b>SSTL</b> and <b>HSTL</b> I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: <i>Single-Ended Voltage Referenced I/O Standard</i> 		
	t <sub>C</sub>	High-speed receiver and transmitter input and output clock period.		
	TCCS (channel- to-channel-skew)	The timing difference between the fastest and slowest output edges, including $t_{c0}$ variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under <b>SW</b> in this table).		
		High-speed I/O block—Duty cycle on the high-speed transmitter output clock.		
T	t <sub>DUTY</sub>	<b>Timing Unit Interval (TUI)</b> The timing budget allowed for skew, propagation delays, and the data sampling window. (TUI = $1/(\text{receiver input clock frequency multiplication factor}) = t_c/w)$		
	t <sub>FALL</sub>	Signal high-to-low transition time (80-20%) Cycle-to-cycle jitter tolerance on the PLL clock input.		
	t <sub>INCCJ</sub>			
	t <sub>OUTPJ_IO</sub>	Period jitter on the general purpose I/O driven by a PLL.		
	t <sub>outpj_dc</sub>	Period jitter on the dedicated clock output driven by a PLL.		
	<b>t</b> <sub>RISE</sub>	Signal low-to-high transition time (20-80%)		
U	_	_		

# **Document Revision History**

Table 61 lists the revision history for this chapter.

 Table 61. Document Revision History (Part 1 of 3)

Date	Version	Changes	
June 2018	3.9	<ul> <li>Added the "Stratix V Device Overshoot Duration" figure.</li> </ul>	
		<ul> <li>Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.</li> </ul>	
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "PS Timing Parameters for Stratix V Devices" table.</li> </ul>	
		<ul> <li>Changed the condition for 100-Ω R<sub>D</sub> in the "OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices" table.</li> </ul>	
April 2017	3.8	<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table</li> </ul>	
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1" table.</li> </ul>	
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1" table.</li> </ul>	
		<ul> <li>Changed the minimum number of clock cycles value in the "Initialization Clock Source Option and the Maximum Frequency" table.</li> </ul>	
June 2016	3.7	<ul> <li>Added the V<sub>ID</sub> minimum specification for LVPECL in the "Differential I/O Standard Specifications for Stratix V Devices" table</li> </ul>	
Julie 2010		<ul> <li>Added the I<sub>OUT</sub> specification to the "Absolute Maximum Ratings for Stratix V Devices" table.</li> </ul>	
December 2015	3.6	<ul> <li>Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.</li> </ul>	
December 2015	3.5	<ul> <li>Changed the transmitter, receiver, and ATX PLL data rate specifications in the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	
December 2015		<ul> <li>Changed the configuration .rbf sizes in the "Uncompressed .rbf Sizes for Stratix V Devices" table.</li> </ul>	
		• Changed the data rate specification for transceiver speed grade 3 in the following tables:	
		<ul> <li>"Transceiver Specifications for Stratix V GX and GS Devices"</li> </ul>	
July 2015	3.4	<ul> <li>"Stratix V Standard PCS Approximate Maximum Date Rate"</li> </ul>	
		<ul> <li>"Stratix V 10G PCS Approximate Maximum Data Rate"</li> </ul>	
		<ul> <li>Changed the conditions for reference clock rise and fall time, and added a note to the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	
		<ul> <li>Added a note to the "Minimum differential eye opening at receiver serial input pins" specification in the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	
		<ul> <li>Changed the t<sub>co</sub> maximum value in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table.</li> </ul>	
		<ul> <li>Removed the CDR ppm tolerance specification from the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	